

Test report No.

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: 30FE0167-HO-02-A-R1

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: April 20, 2011 : PYABH-610

RADIO TEST REPORT

Test Report No.: 30FE0167-HO-02-A-R1

Applicant

Nokia Corporation

Type of Equipment

Nokia Bluetooth Stereo Headset

Model No.

BH-610

FCC ID

PYABH-610

Test regulation

FCC Part 15 Subpart C: 2010

Test Result

Complied

- 1. This test report shall not be reproduced in full or partial, without the written approval of UL Japan, Inc.
- The results in this report apply only to the sample tested.
- This sample tested is in compliance with the above regulation.
- 4. The test results in this report are traceable to the national or international standards.
- This test report must not be used by the customer to claim product certification, approval, or endorsement by NVLAP, NIST, or any agency of the Federal Government.
- This report is a revised version of 30FE0167-HO-02-A. 30FE0167-HO-02-A is replaced with this report.

Date of test:

March 25 to 27, 2011

Representative test engineer:

> Norihisa Hashimoto Engineer of WiSE Japan, **UL Verification Service**

Approved by:

Mitsuru Fujimura Leader of WiSE Japan, **UL Verification Service**



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SECTION 1: Customer information

Company Name : Nokia Corporation

Address : Joensuunkatu7, FIN-24100, Salo, FINLAND

Telephone Number : +358 7180 08000 Facsimile Number : +358 7180 45220 Contact Person : Tero Lehtinen

SECTION 2: Equipment under test (E.U.T.)

2.1 Identification of E.U.T.

Type of Equipment : Nokia Bluetooth Stereo Headset

Model No. : BH-610

Serial No. : Refer to Section 4, Clause 4.2

Rating : DC3.7V Receipt Date of Sample : March 24, 2011

Country of Mass-production : China

Condition of EUT : Production prototype

(Not for Sale: This sample is equivalent to mass-produced items.)

Modification of EUT : No Modification by the test lab

2.2 Product Description

This product is Nokia Bluetooth Stereo Headset for electric device which support Bluetooth wireless technology. And this product can connect Bluetooth with the mobile phone for NFC with the NFC tag.

General Specification

Clock frequency(ies) in the system : 26MHz

Radio Specification

[Bluetooth (Ver. 2.1 with EDR function)]

Radio Type : Transceiver Frequency of Operation : 2402-2480MHz

Modulation : FHSS (DH5: GFSK, 2DH5: π/4-DQPSK, 3DH5: 8DPSK)

Mode of operation : Half-Duplex Method of Frequency Generation : Crystal

Power Supply (radio part input) : DC 3.0V – 4.2V Antenna type : Inverted F Antenna Antenna Gain : Max 0.8dBi

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SECTION 3: Test specification, procedures & results

3.1 Test Specification

Test Specification : FCC Part 15 Subpart C: 2010, final revised on December 6, 2010 and effective

January 5, 2011

Title : FCC 47CFR Part15 Radio Frequency Device Subpart C Intentional Radiators

Section 15.207 Conducted limits

Section 15.247 Operation within the bands 902-928MHz,

2400-2483.5MHz, and 5725-5850MHz

3.2 Procedures and results

Item	Test Procedure	Specification	Worst Margin	Results	Remarks
Conducted Emission	FCC: ANSI C63.4:2003 7. AC powerline conducted emission measurements IC: RSS-Gen 7.2.4	FCC: Section 15.207 IC: RSS-Gen 7.2.4	QP 31.6dB, 0.49512MHz, L AV 28.9dB, 0.49512MHz, L	Complied	-
Carrier Frequency Separation	FCC: FCC Public Notice DA 00-705	FCC: Section15.247(a)(1) IC: RSS-210 A8.1 (b)		Complied	Conducted
20dB Bandwidth	FCC: FCC Public Notice DA 00-705	FCC: Section15.247(a)(1) IC: RSS-210 A8.1 (a)		Complied	Conducted
Number of Hopping Frequency	FCC: FCC Public Notice DA 00-705	FCC: Section15.247(a)(1)(iii) IC: RSS-210 A8.1 (d)	See data.	Complied	Conducted
Dwell time	FCC: FCC Public Notice DA 00-705	FCC: Section15.247(a)(1)(iii) IC: RSS-210 A8.1 (d)		Complied	Conducted
Maximum Peak Output Power	FCC: FCC Public Notice DA 00-705 IC: RSS-Gen 4.8	FCC: Section15.247(a)(b)(1) IC: RSS-210 A8.4 (2)		Complied	Conducted
Spurious Emission & Band Edge Compliance	FCC: FCC Public Notice DA 00-705 IC: RSS-Gen 4.9 RSS-Gen 4.10	FCC: Section15.247(d) IC: RSS-210 A8.5 RSS-Gen 6 and 7.2.3	4.1dB 2483.500MHz, AV, Vert.	Complied	Conducted/ Radiated

^{*} In case any questions arise about test procedure, ANSI C63.4: 2003 is also referred.

FCC 15.31 (e)

The EUT is a battery-operated device and test was performed with the full-charged battery. Therefore, this EUT complies with the requirement.

FCC Part 15.203 Antenna requirement

It is impossible for end users to replace the antenna, because the antenna is mounted inside of the EUT. Therefore, the equipment complies with the antenna requirement of Section 15.203.

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3.3 Addition to standard

Item	Test Procedure	Specification	Worst margin	Results	Remarks
99% Occupied	IC: RSS-Gen 4.6.1	IC: RSS-Gen 4.6.1	N/A	-	Conducted
Bandwidth					

Other than above, no addition, exclusion nor deviation has been made from the standard.

3.4 Uncertainty

EMI

The following uncertainties have been calculated to provide a confidence level of 95% using a coverage factor k=2.

Test room	Conducted emission
(semi-	(<u>+</u> dB)
anechoic	150kHz-30MHz
chamber)	
No.1	3.1dB
No.2	3.3dB
No.3	3.7dB
No.4	3.2dB

Test room	Radiated emission						
(semi-		(3m*)	(<u>+</u> dB)		(1m*))(<u>+</u> dB)	$(0.5\text{m*})(\underline{+}\text{dB})$
anechoic chamber)	9kHz -30MHz	30MHz -300MHz	300MHz -1GHz	1GHz -10GHz	10GHz -18GHz	18GHz -26.5GHz	26.5GHz -40GHz
No.1	3.5dB	5.1dB	5.2dB	4.8dB	5.1dB	4.4dB	4.3dB
No.2	4.0dB	5.1dB	5.2dB	4.8dB	5.0dB	4.3dB	4.2dB
No.3	4.2dB	4.7dB	5.2dB	4.8dB	5.0dB	4.5dB	4.2dB
No.4	4.0dB	5.0dB	5.1dB	4.8dB	5.0dB	5.1dB	4.2dB

^{*3}m/1m/0.5m = Measurement distance

Power meter (<u>+</u> dB)				
Below 1GHz	Above 1GHz			
1.0dB	1.0dB			

Antenna terminal conducted emission			Antenna terminal	conducted emission	Channel power
and	Power density (-	<u>+</u> dB)	(<u>+</u> dB)		(<u>+</u> dB)
Below 1GHz	1GHz-3GHz	3GHz-18GHz	18GHz-26.5GHz	26.5GHz-40GHz	
1.0dB	1.1dB	2.7dB	3.2dB	3.3dB	1.5dB

Conducted Emission test

The data listed in this test report has enough margin, more than the site margin.

Radiated emission test(3m)

The data listed in this report meets the limits unless the uncertainty is taken into consideration.

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3.5 Test Location

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1 elephone . +81 396 24	FCC	IC Registration	Width x Depth x	Size of	Other
	Registration Number	Number	Height (m)	reference ground plane (m) / horizontal conducting plane	rooms
No.1 semi-anechoic chamber	313583	2973C-1	19.2 x 11.2 x 7.7m	7.0 x 6.0m	No.1 Power source room
No.2 semi-anechoic chamber	655103	2973C-2	7.5 x 5.8 x 5.2m	4.0 x 4.0m	-
No.3 semi-anechoic chamber	148738	2973C-3	12.0 x 8.5 x 5.9m	6.8 x 5.75m	No.3 Preparation room
No.3 shielded room	-	-	4.0 x 6.0 x 2.7m	N/A	-
No.4 semi-anechoic chamber	134570	2973C-4	12.0 x 8.5 x 5.9m	6.8 x 5.75m	No.4 Preparation room
No.4 shielded room	-	-	4.0 x 6.0 x 2.7m	N/A	-
No.5 semi-anechoic chamber	-	-	6.0 x 6.0 x 3.9m	6.0 x 6.0m	-
No.6 shielded room	-	-	4.0 x 4.5 x 2.7m	4.75 x 5.4 m	-
No.6 measurement room	-	-	4.75 x 5.4 x 3.0m	4.75 x 4.15 m	-
No.7 shielded room	-	-	4.7 x 7.5 x 2.7m	4.7 x 7.5m	-
No.8 measurement room	-	-	3.1 x 5.0 x 2.7m	N/A	-
No.9 measurement room	-	-	8.0 x 4.5 x 2.8m	2.0 x 2.0m	-
No.10 measurement room	-	-	2.6 x 2.8 x 2.5m	2.4 x 2.4m	-
No.11 measurement room	-	-	3.1 x 3.4 x 3.0m	2.4 x 3.4m	-

^{*} Size of vertical conducting plane (for Conducted Emission test): 2.0 x 2.0m for No.1, No.2, No.3, and No.4 semi-anechoic chambers and No.3 and No.4 shielded rooms.

3.6 Test set up, Data of EMI, and Test instruments

Refer to APPENDIX.

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SECTION 4: Operation of E.U.T. during testing

4.1 Operating Mode(s)

Bluetooth (BT): Transmitting (Tx), Payload: PRBS9

Inquiry

Details of Operating Mode(s)

Test Item	Mode	Tested frequency
Conducted Emission,	Tx (Hopping off) DH5, 3DH5	2402MHz
Spurious Emission		2441MHz
(Conducted/Radiated)		2480MHz
Carrier Frequency Separation	Tx (Hopping on) DH5, 3DH5	2402MHz
	Inquiry	2441MHz
		2480MHz
20dB Bandwidth	Tx (Hopping off) DH5, 3DH5	2402MHz
		2441MHz
		2480MHz
	Inquiry	2440MHz
Number of Hopping Frequency	Tx (Hopping on) DH5, 3DH5	-
	Inquiry	
Dwell time	Tx (Hopping on),	-
	-DH1, DH3, DH5	
	-3DH1, 3DH3, 3DH5	
	Inquiry	
Maximum Peak Output Power	Tx (Hopping off) DH5, 3DH5	2402MHz
		2441MHz
		2480MHz
	Inquiry	2440MHz
Band Edge Compliance	Tx DH5, 3DH5	2402MHz
(Conducted)	-Hopping on	2480MHz
	-Hopping off	
99% Occupied Bandwidth	Tx DH5, 3DH5	2402MHz
-	-Hopping on	2441MHz
	-Hopping off	2480MHz
	Inquiry	

^{*}As a result of preliminary test, the formal test was performed with the above modes, which had the maximum payload length (except Dwell time test)

All the tests were performed with DH5 and 3DH5.

*EUT has the power settings by the software as follows;

Power settings: BDR: Ext.=255, Int.=57

EDR: Ext.=255, Int.=59

Bluesuite. Version 2.2 HW version: 1.01 SW version: 0.8 Mech vesion: 0.6

Any conditions under the normal use do not exceed the condition of setting.

In addition, end users cannot change the settings of the output power of the product.

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^{*}Maximum Peak Output Power was also confirmed with 2DH5 (π /4-DQPSK) preliminarily.

^{*}This setting of software is the worst case.

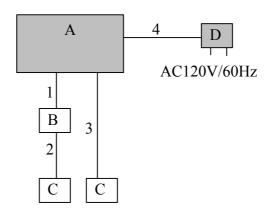
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4.2 Configuration and peripherals



Description of EUT

20001	puon or DC 1				
No.	Item	Model number	Serial number	Manufacturer	Remarks
_	Nokia Bluetooth Stereo	BH-610	001 *1)	NOKIA	EUT
Α	Headset		002 *2)		
В	Microphone	-	-	NOKIA	-
С	Earphone	-	-	NOKIA	-
D	AC Adapter *3)	AC-4E	4419297442021348012;	NOKIA	EUT
שו			0675384		

^{*1)} Used for Antenna Terminal conducted test

Each model has variant models, and the suffix of the model name (ex. AC-3"X") is replaced with E, X, AR, U, A, C, K, and B.

List of cables used

No.	Name	Length (m)	Shield		Remarks
			Cable	Connector	
1	Microphone & Earphone Cable	0.4	Unshielded	Unshielded	-
2	Earphone Cable	0.1	Unshielded	Unshielded	-
3	Earphone Cable	0.5	Unshielded	Unshielded	-
4	AC Cable	1.8	Unshielded	Unshielded	-

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^{*} Cabling and setup(s) were taken into consideration and test data was taken under worse case conditions.

^{*2)} Used for Conducted Emission test and Radiated Emission test

^{*3)} The test was performed with worst model: "AC-4E" as a representative after having compared with following models: -AC-3E, AC-4E, AC-5E, AC-8E, AC-15U, DC-4

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SECTION 5: Conducted Emission

Test Procedure and conditions

EUT was placed on a urethane platform of nominal size, 1.0m by 0.5m, raised 0.8m above the conducting ground plane. The rear of tabletop was located 40cm to the vertical conducting plane. The rear of EUT, including peripherals aligned and flushed with rear of tabletop. All other surfaces of tabletop were at least 80cm from any other grounded conducting surface. EUT was located 80cm from a Line Impedance Stabilization Network (LISN)/ Artificial mains Network (AMN) and excess AC cable was bundled in center.

For the tests on EUT with other peripherals (as a whole system)

I/O cables that were connected to the peripherals were bundled in center. They were folded back and forth forming a bundle 30cm to 40cm long and were hanged at a 40cm height to the ground plane. All unused 50ohm connectors of the LISN(AMN) were resistivity terminated in 50ohm when not connected to the measuring equipment.

The AC Mains Terminal Continuous disturbance Voltage has been measured with the EUT in a Semi Anechoic Chamber . The EUT was connected to a LISN (AMN).

An overview sweep with peak detection has been performed.

The test results and limit are rounded off to one decimal place, so some differences might be observed.

Detector : QP and AV
Measurement range : 0.15-30MHz
Test data : APPENDIX
Test result : Pass

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SECTION 6: Radiated Spurious Emission

Test Procedure

EUT was placed on a urethane platform of nominal size, 1.0m by 0.5m, raised 0.8m above the conducting ground plane.

The Radiated Electric Field Strength has been measured in a Semi Anechoic Chamber with a ground plane.

The height of the measuring antenna varied between 1 and 4m and EUT was rotated a full revolution in order to obtain the maximum value of the electric field strength.

The measurements were performed for both vertical and horizontal antenna polarization with the Test Receiver, or the Spectrum Analyzer.

The measurements were made with the following detector function of the test receiver and the Spectrum analyzer (in linear mode).

The test was made with the detector (RBW/VBW) in the following table.

When using Spectrum analyzer, the test was made with adjusting span to zero by using peak hold.

Test Antennas are used as below;

Frequency	30MHz to 300MHz	300MHz to 1GHz	Above 1GHz
Antenna Type	Biconical	Logperiodic	Horn

In any 100kHz bandwidth outside the restricted band in which the spread spectrum intentional radiator is operating, the radio frequency power that is produced by the intentional radiator confirmed 20dB below that in the 100kHz bandwidth within the band that contains the highest level of the desired power, based on a radiated measurement.

20dBc was applied to the frequency over the limit of FCC 15.209 / Table 5 of RSS-Gen 7.2.5 (IC) and outside the restricted band of FCC15.205 / Table 3 of RSS-Gen 7.2.2 (IC).

estricted said of 1 cereizot / Tubic e of Risk Gen /12/2 (1e).										
Frequency	Below 1GHz	Above 1GHz	20dBc							
Instrument used	Test Receiver	Spectrum Analyzer	Spectrum Analyzer							
Detector	QP	PK	AV	PK						
IF Bandwidth	BW 120kHz(T/R)	RBW: 1MHz	RBW: 1MHz	RBW: 100kHz						
		VBW: 3MHz	VBW: 10Hz	VBW: 300kHz (S/A)						
			or							
			RBW: 1MHz							
			VBW: 270Hz *1)							
Test Distance	3m	3m (below 10GHz),		3m (below 10GHz),						
		1m*2) (above 10GHz	1m*2) (above 10GHz)							

^{*1)} Used for the band edge of the carrier and the harmonics that can be measured. The VBW is based on the inverse of the duty cycle (see Appendix).

- The carrier level and noise levels were confirmed at each position of X, Y and Z axes of EUT to see the position of maximum noise, and the test was made at the position that has the maximum noise.

The test results and limit are rounded off to one decimal place, so some differences might be observed.

Measurement range : 30M-25GHz
Test data : APPENDIX
Test result : Pass

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^{*2)} Distance Factor: $20 \times \log (3.0 \text{m}/1.0 \text{m}) = 9.5 \text{dB}$

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SECTION 7: Antenna Terminal Conducted Tests

Test Procedure

The tests were made with below setting connected to the antenna port.

Test	Span	RBW	VBW	Sweep time	Detector	Trace	Instrument used
20dB Bandwidth	3MHz	30kHz	100kHz	Auto	Peak	Max Hold	Spectrum Analyzer
99% Occupied Bandwidth	Enough width to display 20dB Bandwidth	1 to 3% of Span	Three times of RBW	Auto	Peak	Max Hold	Spectrum Analyzer
Maximum Peak Output Power	-	-	ı	Auto	Peak	-	Power Meter (Sensor: 50MHz BW)
Carrier Frequency Separation	3MHz or 5MHz	100kHz	300kHz	Auto	Peak	Max Hold	Spectrum Analyzer
Number of Hopping Frequency	30MHz	300kHz	1MHz	Auto	Peak	Max Hold	Spectrum Analyzer
Dwell Time	Zero Span	1MHz	3MHz	As necessary capture the entire dwell time per hopping channel	Peak	Max Hold	Spectrum Analyzer
Conducted Spurious Emission *	Range: 9kHz-150kHz	200Hz	620Hz	Auto	Peak	Max Hold	Spectrum Analyzer
	Range: 150kHz-30MHz	9.1kHz	27kHz				
	Range: 30MHz-25GHz (Less or equal to 5GHz)	100kHz	300kHz				
Conducted Spurious Emission Band Edge compliance	20MHz	300kHz	1MHz	Auto	Peak	Max Hold	Spectrum Analyzer

^{*} In the frequency range below 30MHz, RBW was narrowed to separate the noise contents.

Then, wide-band noise near the limit was checked separately, however the noise was not detected as shown in the chart. (9kHz-150kHz:RBW=200Hz, 150kHz-30MHz:RBW=10kHz)

The test results and limit are rounded off to two decimals place, so some differences might be observed.

Test data : APPENDIX

: Pass Test result

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